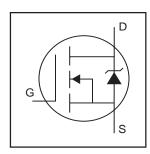
# International Rectifier

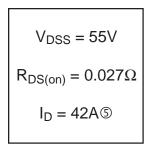
#### PD-91334E

# IRLR/U2905

### HEXFET® Power MOSFET

- Logic-Level Gate Drive
- Ultra Low On-Resistance
- Surface Mount (IRLR2905)
- Straight Lead (IRLU2905)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated

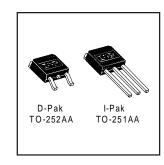




#### **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The D-PAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V	42 ⑤	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V	30	A
I <sub>DM</sub>	Pulsed Drain Current ①	160	
$P_D @ T_C = 25 ° C$	Power Dissipation	110	W
	Linear Derating Factor	0.71	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 16	V
E <sub>AS</sub>	Single Pulse Avalanche Energy@	210	mJ
I <sub>AR</sub>	Avalanche Current ①	25	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①	11	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	

#### Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.4	
$R_{\theta JA}$	Case-to-Ambient (PCB mount)**		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

<sup>\*\*</sup> When mounted on 1" square PCB (FR-4 or G-10 Material).
For recommended footprint and soldering techniques refer to application note #AN-994
WWW.irf.com



# Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	55	_		V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.070		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
			_	0.027		V <sub>GS</sub> = 10V, I <sub>D</sub> = 25A ⊕
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		_	0.030	W	V <sub>GS</sub> = 5.0V, I <sub>D</sub> = 25A ④
			_	0.040		V <sub>GS</sub> = 4.0V, I <sub>D</sub> = 21A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0	_	2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
g <sub>fs</sub>	Forward Transconductance	21			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 25A⑦
	Drain-to-Source Leakage Current		25	μA	$V_{DS} = 55V, V_{GS} = 0V$	
I <sub>DSS</sub>	Dialii-to-Source Leakage Current			250	μΑ	V <sub>DS</sub> = 44V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
Lana	Gate-to-Source Forward Leakage		_	100	nA	V <sub>GS</sub> = 16V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage		_	-100		V <sub>GS</sub> = -16V
Qg	Total Gate Charge		_	48		I <sub>D</sub> = 25A
Q <sub>gs</sub>	Gate-to-Source Charge		_	8.6	nC	$V_{DS} = 44V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge		_	25		$V_{GS} = 5.0V$ , See Fig. 6 and 13 $\oplus$ $\oslash$
t <sub>d(on)</sub>	Turn-On Delay Time		11			V <sub>DD</sub> = 28V
t <sub>r</sub>	Rise Time		84		ns	$I_D = 25A$
t <sub>d(off)</sub>	Turn-Off Delay Time		26		115	$R_G = 3.4\Omega, V_{GS} = 5.0V$
t <sub>f</sub>	FallTime		15			$R_D = 1.1\Omega$ , See Fig. 10 $\oplus$ $\oslash$
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead,
					nH	6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5	_		from package GV
						and center of die contact® s
C <sub>iss</sub>	Input Capacitance	_	1700	_		$V_{GS} = 0V$
Coss	Output Capacitance		400		pF	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		150			f = 1.0 MHz, See Fig. 5

### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current			40.0		MOSFET symbol	
	(Body Diode)		42 <sup>(5)</sup>	A	showing the		
I <sub>SM</sub>	Pulsed Source Current				400		integral reverse
	(Body Diode) ①		160	50	p-n junction diode.		
V <sub>SD</sub>	Diode Forward Voltage	_		1.3	٧	$T_J = 25^{\circ}C$ , $I_S = 25A$ , $V_{GS} = 0V$ ④	
t <sub>rr</sub>	Reverse Recovery Time		80	120	ns	$T_J = 25^{\circ}C, I_F = 25A$	
Q <sub>rr</sub>	Reverse RecoveryCharge	_	210	320	nC	di/dt = 100A/µs ④⑦	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

2

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)  $V_{DD} = 25V$ , starting  $T_J = 25^{\circ}C$ ,  $L = 470 \mu H$
- $R_G = 25\Omega$ ,  $I_{AS} = 25A$ . (See Figure 12)
- $3 I_{SD} \le 25A$ , di/dt  $\le 270A/\mu s$ ,  $V_{DD} \le V_{(BR)DSS}$ ,  $T_J\!\le 175^\circ C$
- ④ Pulse width  $\leq$  300µs; duty cycle  $\leq$  2%.

- © Caculated continuous current based on maximum allowable junction temperature; Package limitation current = 20A.
- 6 This is applied for I-PAK, L<sub>S</sub> of D-PAK is measured between lead and center of die contact.
- 7 Uses IRLZ44N data and test conditions.

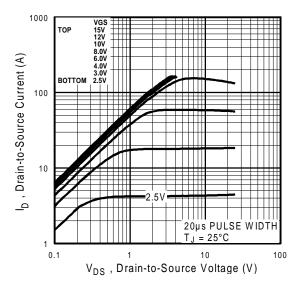


Fig 1. Typical Output Characteristics

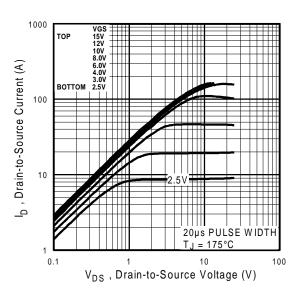


Fig 2. Typical Output Characteristics

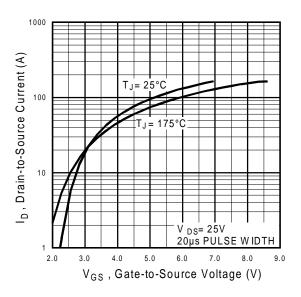
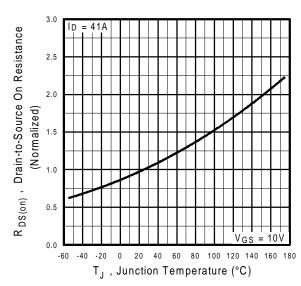
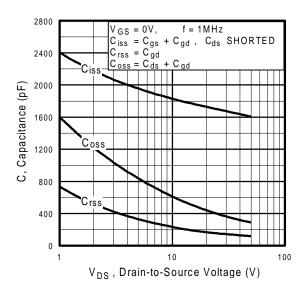


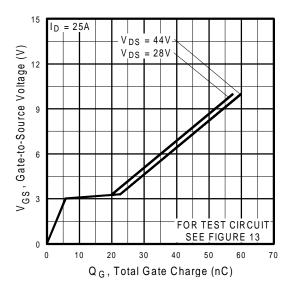
Fig 3. Typical Transfer Characteristics



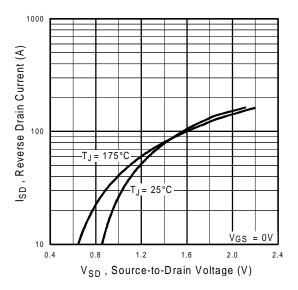
**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

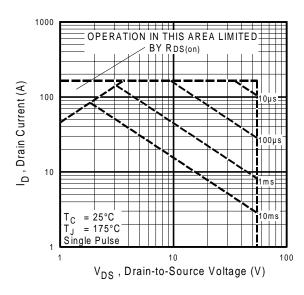
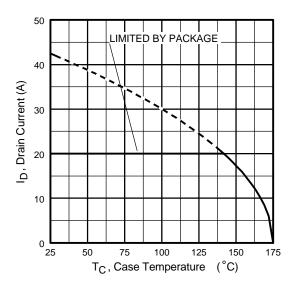


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

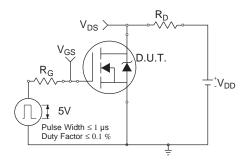


Fig 10a. Switching Time Test Circuit

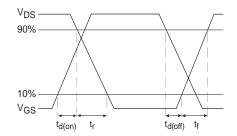


Fig 10b. Switching Time Waveforms

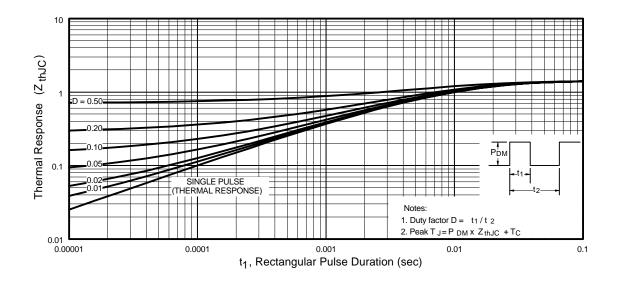


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

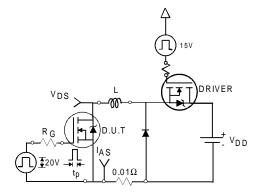


Fig 12a. Unclamped Inductive Test Circuit

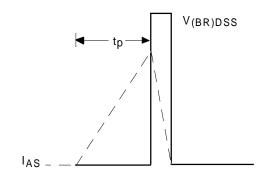


Fig 12b. Unclamped Inductive Waveforms

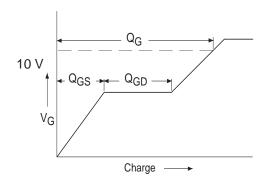
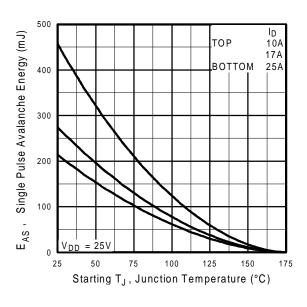


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

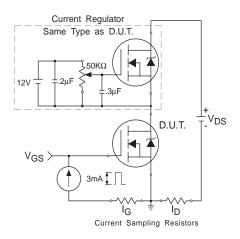
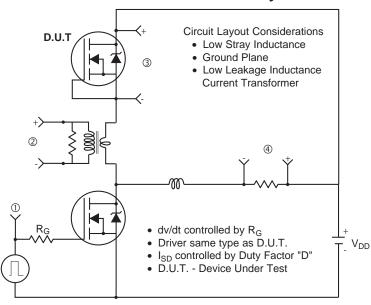
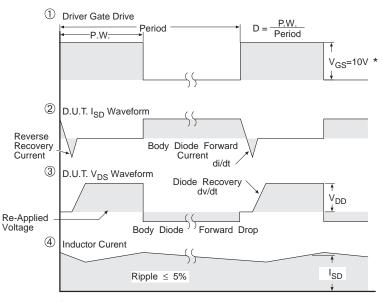


Fig 13b. Gate Charge Test Circuit

# Peak Diode Recovery dv/dt Test Circuit





\*  $V_{GS} = 5V$  for Logic Level Devices

Fig 14. For N-Channel HEXFETS

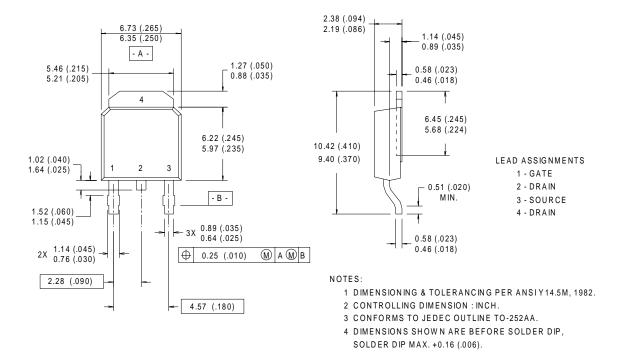
International

TOR Rectifier

# Package Outline

#### TO-252AA Outline

Dimensions are shown in millimeters (inches)



# Part Marking Information TO-252AA (D-PARK)

EXAMPLE: THIS IS AN IRFR120

WITH ASSEMBLY LOT CODE 9U1P

INTERNATIONAL
RECTIFIER
LOGO
IRFR
120
9U 1P
ASSEMBLY
LOT CODE
SECOND PORTION
OF PART NUMBER

International

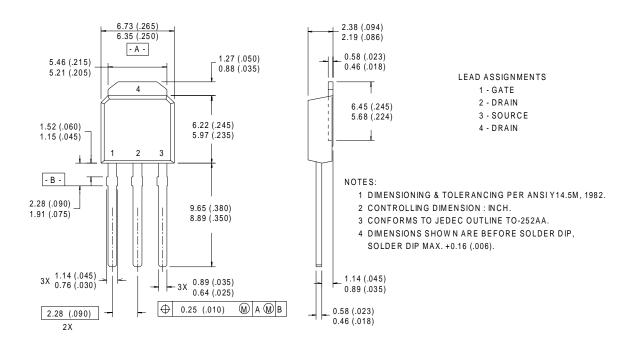
TOR Rectifier

IRLR/U2905

# Package Outline

#### TO-251AA Outline

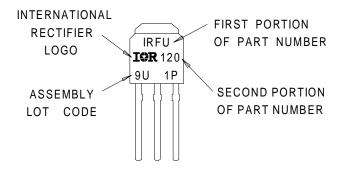
Dimensions are shown in millimeters (inches)



# Part Marking Information TO-251AA (I-PARK)

EXAMPLE: THIS IS AN IRFU120

WITH ASSEMBLY LOT CODE 9U1P

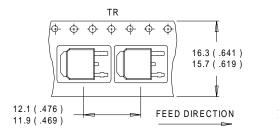


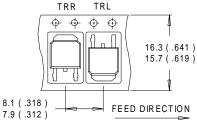
International IOR Rectifier

# Tape & Reel Information

#### TO-252AA

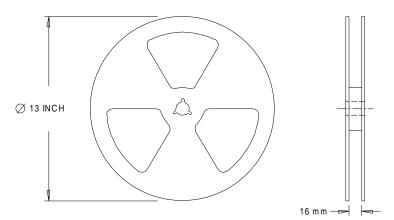
Dimensions are shown in millimeters (inches)





#### NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS ( INCHES ).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



#### NOTES:

1. OUTLINE CONFORMS TO EIA-481.

# International IOR Rectifier

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